June 2007



## FDS4435BZ

# P-Channel PowerTrench<sup>®</sup> MOSFET -30V, -8.8A, 20m $\Omega$

#### **Features**

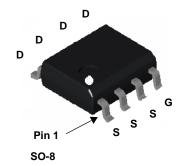
- Max  $r_{DS(on)} = 20m\Omega$  at  $V_{GS} = -10V$ ,  $I_D = -8.8A$
- Max  $r_{DS(on)} = 35m\Omega$  at  $V_{GS} = -4.5V$ ,  $I_D = -6.7A$
- Extended V<sub>GSS</sub> range (-25V) for battery applications
- HBM ESD protection level of ±3.8KV typical (note 3)
- High performance trench technology for extremely low r<sub>DS(on)</sub>
- High power and current handling capability
- Termination is Lead-free and RoHS compliant

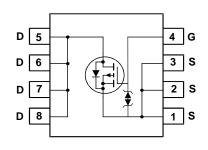


#### **General Description**

This P-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench® process that has been especially tailored to minimize the on-state resistance.

This device is well suited for Power Management and load switching applications common in Notebook Computers and Portable Battery Packs.





### **MOSFET Maximum Ratings** T<sub>A</sub> = 25°C unless otherwise noted

Symbol	Param		Ratings	Units		
V <sub>DS</sub>	Drain to Source Voltage			-30	V	
$V_{GS}$	Gate to Source Voltage			±25	V	
1	Drain Current -Continuous	T <sub>A</sub> = 25°C	(Note 1a)	-8.8	۸	
<sup>I</sup> D	-Pulsed			-50	— A	
D	Power Dissipation $T_A = 25^{\circ}C$ (Note 1a)		(Note 1a)	2.5	W	
$P_{D}$	Power Dissipation $T_A = 25^{\circ}C$ (Note 1b)		(Note 1b)	1.0	VV	
E <sub>AS</sub>	Single Pulse Avalanche Energy (Note 4)			24	mJ	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range			-55 to +150	°C	

#### **Thermal Characteristics**

$R_{\theta JC}$	Thermal Resistance, Junction to Case	25	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a	50	C/VV

#### **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDS4435BZ	FDS4435BZ	SO-8	13"	12mm	2500units

## **Electrical Characteristics** $T_J = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	acteristics					
$BV_{DSS}$	Drain to Source Breakdown Voltage	$I_D = -250 \mu A, V_{GS} = 0 V$	-30			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	nperature $I_D = -250\mu\text{A}$ , referenced to 25°C		-21		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = -24V,  V_{GS} = 0V$			1	μΑ
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = \pm 25V, V_{DS} = 0V$			±10	μΑ

#### On Characteristics

V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = -250 \mu A$	-1	-2.1	-3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = -250\mu\text{A}$ , referenced to 25°C		6		mV/°C
		$V_{GS} = -10V, I_D = -8.8A$		16	20	
r <sub>DS(on)</sub>	r <sub>DS(on)</sub> Static Drain to Source On Resistance	$V_{GS} = -4.5V$ , $I_D = -6.7A$		26	35	mΩ
		$V_{GS} = -10V$ , $I_D = -8.8A$ , $T_J = 125$ °C		22	28	
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = -5V, I_{D} = -8.8A$		24		S

#### **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V 45V V 0V		1385	1845	pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = -15V, V_{GS} = 0V,$ f = 1MHz		275	365	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 – 111112		230	345	pF
$R_g$	Gate Resistance	f = 1MHz		4.5		Ω

## **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time		10	20	ns
t <sub>r</sub>	Rise Time	$V_{DD} = -15V, I_{D} = -8.8A,$ $V_{GS} = -10V, R_{GEN} = 6\Omega$	6	12	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	V <sub>GS</sub> = -10V, R <sub>GEN</sub> = 002	30	48	ns
t <sub>f</sub>	Fall Time		12	22	ns
Qg	Total Gate Charge	V <sub>GS</sub> = 0V to -10V	28	40	nC
Qg	Total Gate Charge	$V_{GS} = 0V \text{ to } -5V$ $V_{DD} = -15V,$ $I_{D} = -8.8A$	16	23	nC
Q <sub>gs</sub>	Gate to Source Charge	I <sub>D</sub> = -0.0A	5.2		nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge		7.4		nC

#### **Drain-Source Diode Characteristics**

$V_{SD}$	Source to Drain Diode Forward Voltage	$V_{GS} = 0V, I_S = -8.8A$ (Note 2)		-0.9	-1.2	V
t <sub>rr</sub>	Reverse Recovery Time	L _ 9.9A di/dt _ 100A/		29	44	ns
Q <sub>rr</sub>	Reverse Recovery Charge	$I_F = -8.8A$ , di/dt = 100A/ $\mu$ s		23	35	nC

<sup>1.</sup> R<sub>0JA</sub> is determined with the device mounted on a 1in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R<sub>0JC</sub> is guaranteed by design while R<sub>0CA</sub> is determined by the user's board design.



a. 50°C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper.



b. 125°C/W when mounted on a minimum pad of 2 oz copper.

- 2. Pulse Test: Pulse Width <  $300\mu$ s, Duty cycle < 2.0%.
- 3. The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.
- 4. Starting  $T_J = 25$  °C, L = 1mH,  $I_{AS} = -7$ A,  $V_{DD} = -30$ V,  $V_{GS} = -10$ V

## Typical Characteristics T<sub>J</sub> = 25°C unless otherwise noted

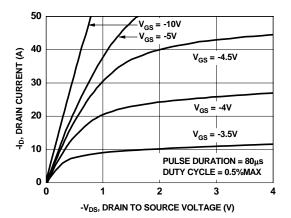


Figure 1. On-Region Characteristics

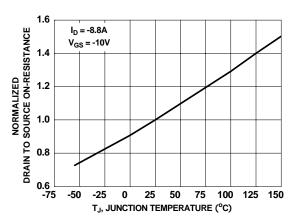


Figure 3. Normalized On-Resistance vs Junction Temperature

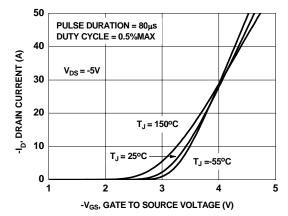


Figure 5. Transfer Characteristics

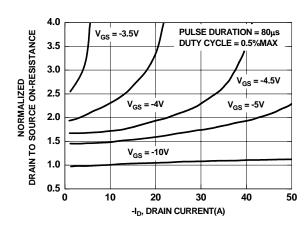


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

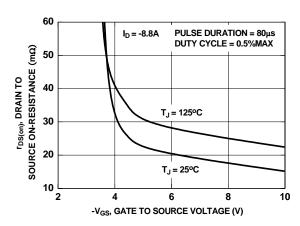


Figure 4. On-Resistance vs Gate to Source Voltage

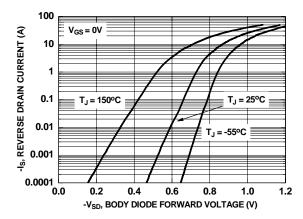


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

## Typical Characteristics T<sub>J</sub> = 25°C unless otherwise noted

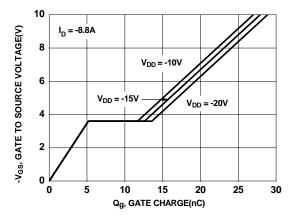


Figure 7. Gate Charge Characteristics

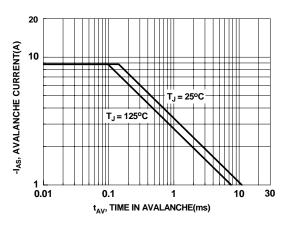


Figure 9. Unclamped Inductive Switching Capability

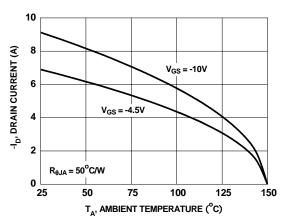


Figure 11. Maximum Continuous Drain Current vs Ambient Temperature

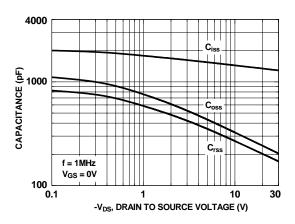


Figure 8. Capacitance vs Drain to Source Voltage

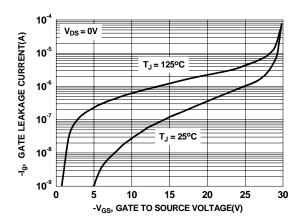


Figure 10. Gate Leakage Current vs Gate to Source Voltage

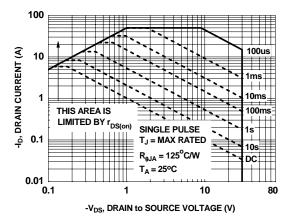


Figure 12. Forward Bias Safe Operating Area

# Typical Characteristics $T_J = 25^{\circ}C$ unless otherwise noted

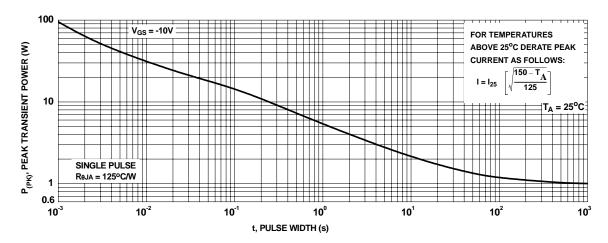


Figure 13. Single Pulse Maximum Power Dissipation

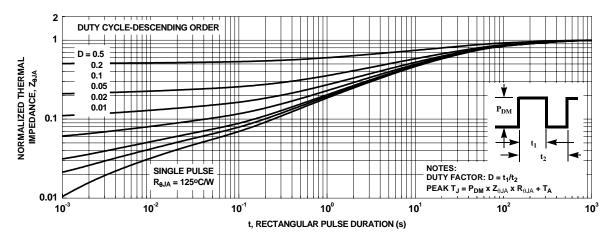


Figure 14. Transient Thermal Response Curve





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